

**Search Notes**

Application/Control No.

10/762,453

Examiner

David E. Martinez

Applicant(s)/Patent under  
Reexamination

CHANG, AN-SHENG

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East see attached	6/8/2006	DM
710/15,17,36,58,59.ccls. 714/1,2,14,47,48.ccls. with keywords and text search	6/8/2006	DM
eDan Inventor Search	6/8/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	6/8/2006	DM